

Search Notes	Application/Control No.	Applicant(s)/Patent Under Reexamination
	10767168	NAKAYA ET AL.
	Examiner	Art Unit
	Riley, Marcus T	2625

SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES

Search Notes	Date	Examiner
(358/496) text search - see search history printouts	5/14/2007	MTR
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Google Search - Search Terms (Image, Head Unit, Direction, Predetermined, Scan, Scanner, Pixel, Update, Alter, Alterable, Micromirror, Plural, Plurality, SRAM, Retard, Slow, Error, Crystal Liquid, Laser, Irradiate, Shut, Shutter, Kanatake, Store, Storage, Memory, Image, Time, Timing,	11/23/2007	MTR

INTERFERENCE SEARCH

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